

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/081,768	CHEN ET AL.	
		Examiner	Art Unit	
		Michael Barr	1762	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,060,121	05-2000	Hidber et al.	427/261
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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N					
O					
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S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages	
X	U	Boonekamp et al., "Adsorption of Nanometer-Sized Palladium Particles on Si(100) Surfaces", LANGMUIR, 10, American Chemical Society, 1994, ppgs. 4089-4094.
	V	
	W	
	X	

**A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(e).)*
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